

Title (en)

METHOD AND DEVICE FOR CHARACTERISING PYRAMIDAL SURFACE STRUCTURES ON A SUBSTRATE

Title (de)

VERFAHREN UND VORRICHTUNG ZUR CHARAKTERISIERUNG VON PYRAMIDALEN OBERFLÄCHENSTRUKTUREN AUF EINEM SUBSTRAT

Title (fr)

PROCÉDÉ ET DISPOSITIF POUR CARACTÉRISER DES STRUCTURES DE SURFACE PYRAMIDALES SUR UN SUBSTRAT

Publication

EP 2572186 A1 20130327 (DE)

Application

EP 11710176 A 20110321

Priority

- DE 102010029133 A 20100519
- EP 2011054216 W 20110321

Abstract (en)

[origin: WO2011144374A1] The invention relates to a method and to a device for characterising pyramidal surface structures on a substrate. It contains the following method steps: irradiating the substrate surface in particular with laser light, capturing a light beam reflection pattern generated by the substrate surface, evaluating the reflection pattern, wherein the intensity of at least one directional pyramidal reflection maximum generated by lateral flanks of the pyramidal surface structure, the intensity of a diffuse reflection band generated by edges of the pyramidal surface structures and the intensity of a flaw maximum generated by flat flaws are determined.

IPC 8 full level

G01N 21/95 (2006.01)

CPC (source: EP)

G01N 21/55 (2013.01); **G01N 21/95** (2013.01)

Citation (search report)

See references of WO 2011144374A1

Designated contracting state (EPC)

AL AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO RS SE SI SK SM TR

DOCDB simple family (publication)

DE 102010029133 A1 20111124; EP 2572186 A1 20130327; WO 2011144374 A1 20111124

DOCDB simple family (application)

DE 102010029133 A 20100519; EP 11710176 A 20110321; EP 2011054216 W 20110321